



# 74AHC595

## 8-Bit Serial-In/Serial-Out or Parallel-Out Shift Register with Output Latches

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### GENERAL DESCRIPTION

The 74AHC595 is a high-speed Si-gate CMOS device. The device is an 8-bit serial-in/serial-out or parallel-out shift register with output latches.

This device features a serial input and a serial standard output for cascading. All of the 8 shift register stages have the asynchronous reset function when active low. When  $\overline{OE}$  is held low, the data in storage register will appear at the output. When  $\overline{OE}$  is held high, all outputs except Q7S are in high-impedance state.

Both the shift register and storage register have separate clocks. The shift register clock (SHCP) is positive-edge triggered. Data is shifted on the positive-going transitions of the SHCP. The storage register clock (STCP) is also positive-edge triggered. The data in each register is transferred to the storage register on a positive-going transition of the STCP. If the SHCP and STCP are connected together, the shift register is always one clock pulse ahead of the storage register.

### FEATURES

- **Wide Operating Voltage Range: 2.0V to 5.5V**
- **Inputs Accept Voltages Higher than the Supply Voltage**
- **All Inputs with Schmitt-Trigger Actions**
- **Balanced Propagation Delays**
- **Operate with CMOS Input Level**
- **-40°C to +125°C Operating Temperature Range**
- **Available in Green TSSOP-16 and SOIC-16 Packages**

### APPLICATIONS

Remote Control Holding Registers  
Serial-to-Parallel Data Conversion

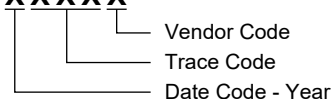
## PACKAGE/ORDERING INFORMATION

MODEL	PACKAGE DESCRIPTION	SPECIFIED TEMPERATURE RANGE	ORDERING NUMBER	PACKAGE MARKING	PACKING OPTION
74AHC595	TSSOP-16	-40°C to +125°C	74AHC595XTS16G/TR	74AHC595 XTS16 XXXXX	Tape and Reel, 4000
	SOIC-16	-40°C to +125°C	74AHC595XS16G/TR	74AHC595XS16 XXXXX	Tape and Reel, 2500

## MARKING INFORMATION

NOTE: XXXXX = Date Code, Trace Code and Vendor Code.

XXXXX



Green (RoHS & HSF): SG Micro Corp defines "Green" to mean Pb-Free (RoHS compatible) and free of halogen substances. If you have additional comments or questions, please contact your SGMICRO representative directly.

ABSOLUTE MAXIMUM RATINGS <sup>(1)</sup>

Supply Voltage, $V_{CC}$ .....	-0.5V to 7V
Input Voltage, $V_I$ .....	-0.5V to 7V
Input Clamping Current, $I_{IK}$ <sup>(2)</sup> ( $V_I < -0.5V$ ).....	-20mA
Output Clamping Current, $I_{OK}$ <sup>(2)</sup> ( $V_O < -0.5V$ or $V_O > V_{CC} + 0.5V$ ).....	$\pm 20mA$
Output Current, $I_O$ ( $V_O = -0.5V$ to $V_{CC} + 0.5V$ ).....	$\pm 25mA$
Supply Current, $I_{CC}$ .....	75mA
Ground Current, $I_{GND}$ .....	-75mA
Junction Temperature <sup>(3)</sup> .....	+150°C
Storage Temperature Range.....	-65°C to +150°C
Lead Temperature (Soldering, 10s).....	+260°C
ESD Susceptibility	
HBM.....	3000V
CDM.....	1000V

## RECOMMENDED OPERATING CONDITIONS

Supply Voltage, $V_{CC}$ .....	2.0V to 5.5V
Input Voltage, $V_I$ .....	0V to 5.5V
Output Voltage, $V_O$ .....	0V to $V_{CC}$
Input Transition Rise and Fall Rate, $\Delta t/\Delta V$	
$V_{CC} = 3.0V$ to $3.6V$ .....	100ns/V (MAX)
$V_{CC} = 4.5V$ to $5.5V$ .....	20ns/V (MAX)
Operating Temperature Range.....	-40°C to +125°C

## OVERSTRESS CAUTION

1. Stresses beyond those listed in Absolute Maximum Ratings may cause permanent damage to the device. Exposure to absolute maximum rating conditions for extended periods may affect reliability. Functional operation of the device at any conditions beyond those indicated in the Recommended Operating Conditions section is not implied.
2. The input and output voltage ratings may be exceeded if the input and output clamp current ratings are observed.
3. The performance capability of a high-performance integrated circuit in conjunction with its thermal environment can create junction temperatures which are detrimental to reliability.

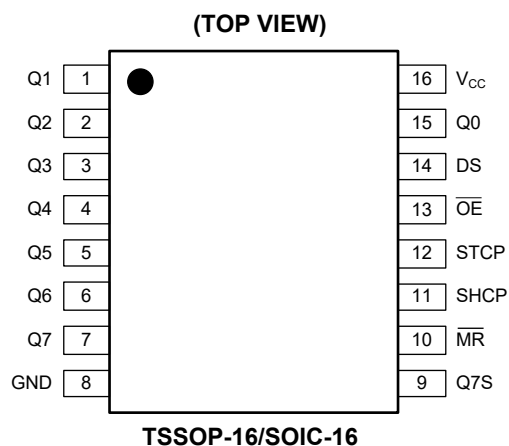
## ESD SENSITIVITY CAUTION

This integrated circuit can be damaged if ESD protections are not considered carefully. SGMICRO recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage. ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because even small parametric changes could cause the device not to meet the published specifications.

## DISCLAIMER

SG Micro Corp reserves the right to make any change in circuit design, or specifications without prior notice.

## PIN CONFIGURATION

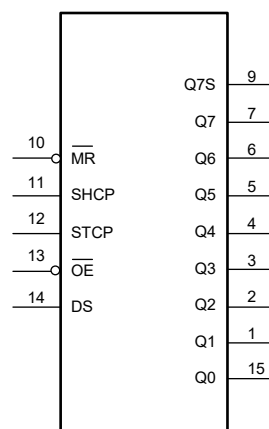
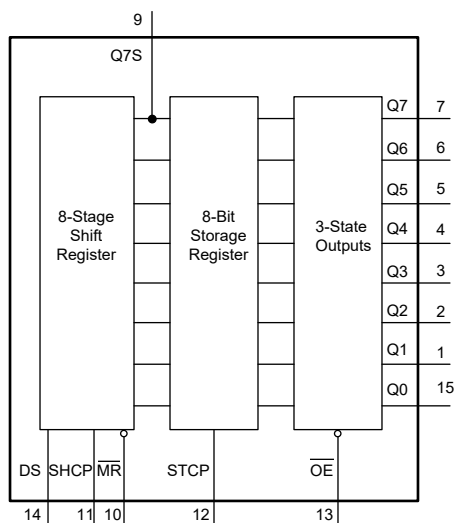


## PIN DESCRIPTION

PIN	NAME	FUNCTION
15, 1, 2, 3, 4, 5, 6, 7	Q0, Q1, Q2, Q3, Q4, Q5, Q6, Q7	Parallel Data Outputs.
8	GND	Ground.
9	Q7S	Serial Data Output.
10	$\overline{\text{MR}}$	Master Reset (Active Low).
11	SHCP	Shift Register Clock Input.
12	STCP	Storage Register Clock Input.
13	$\overline{\text{OE}}$	Output Enable Input (Active Low).
14	DS	Serial Data Input.
16	V <sub>CC</sub>	Supply Voltage.

## 8-Bit Serial-In/Serial-Out or Parallel-Out Shift Register with Output Latches

## LOGIC SYMBOL

[illegible]

## FUNCTION TABLE

CONTROL INPUT				INPUT	OUTPUT		FUNCTION
SHCP	STCP	OE	MR	DS	Q7S	Qn	
X	X	L	L	X	L	NC	A low-level on $\overline{MR}$ only affects the shift registers.
X	↑	L	L	X	L	L	Empty shift register loaded into storage register.
X	X	H	L	X	L	Z	Shift register clear, parallel outputs in high-impedance off-state.
↑	X	L	H	H	Q6S	NC	Logic high-level shifted into shift register Stage 0. Contents of all shift register stages shifted through, e.g. previous state of Stage 6 (internal Q6S) appears on the serial output (Q7S).
X	↑	L	H	X	NC	QnS	Contents of shift register stages (internal QnS) are transferred to the storage register and parallel output stages.
↑	↑	L	H	X	Q6S	QnS	Contents of shift register shifted through, previous contents of the shift register are transferred to the storage register and parallel output stages.

H = High Voltage Level

L = Low Voltage Level

↑ = Low-to-High Clock Transition

Z = High-Impedance State

NC = No Change

X = Don't Care

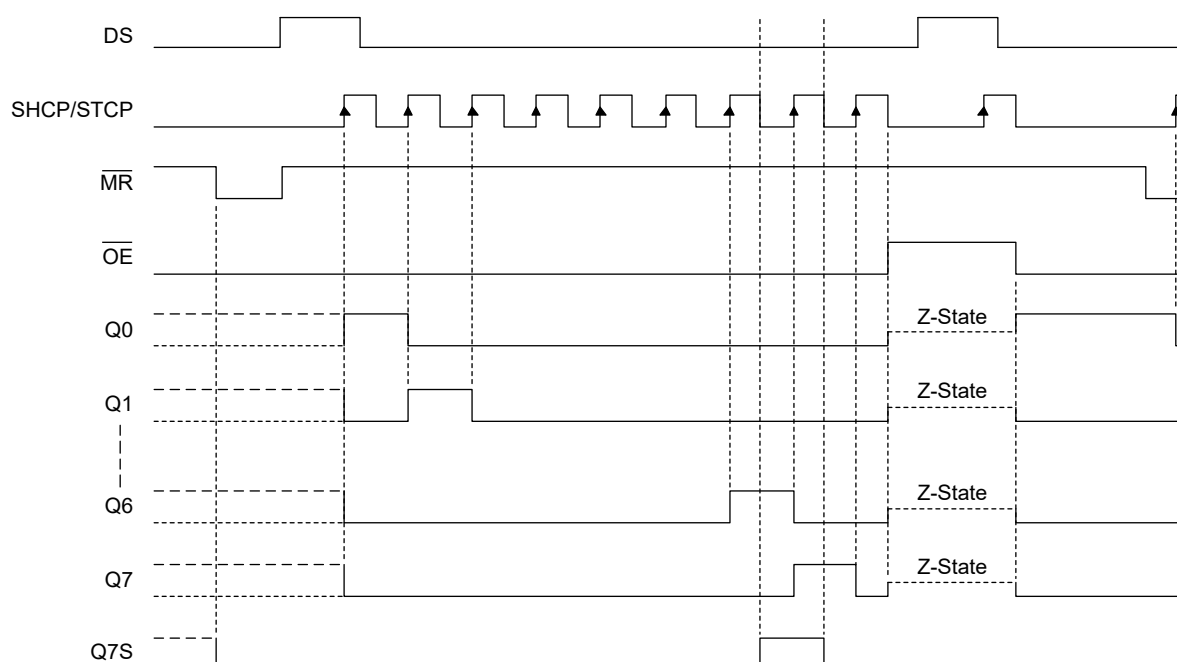


Figure 1. Timing Diagram

## ELECTRICAL CHARACTERISTICS

(Full = -40°C to +125°C, all typical values are measured at T<sub>A</sub> = +25°C, unless otherwise noted.)

PARAMETER	SYMBOL	CONDITIONS		TEMP	MIN	TYP	MAX	UNITS
High-Level Input Voltage	V <sub>IH</sub>	V <sub>CC</sub> = 2.0V		Full	1.5			V
		V <sub>CC</sub> = 3.0V		Full	2.1			
		V <sub>CC</sub> = 5.5V		Full	3.85			
Low-Level Input Voltage	V <sub>IL</sub>	V <sub>CC</sub> = 2.0V		Full			0.5	V
		V <sub>CC</sub> = 3.0V		Full			0.9	
		V <sub>CC</sub> = 5.5V		Full			1.65	
High-Level Output Voltage	V <sub>OH</sub>	V <sub>I</sub> = V <sub>IH</sub> or V <sub>IL</sub>	V <sub>CC</sub> = 2.0V to 4.5V, I <sub>O</sub> = -50μA	Full	V <sub>CC</sub> - 0.1	V <sub>CC</sub> - 0.005		V
			V <sub>CC</sub> = 3.0V, I <sub>O</sub> = -4.0mA	Full	2.4	2.8		
			V <sub>CC</sub> = 4.5V, I <sub>O</sub> = -8.0mA	Full	3.7	4.2		
Low-Level Output Voltage	V <sub>OL</sub>	V <sub>I</sub> = V <sub>IH</sub> or V <sub>IL</sub>	V <sub>CC</sub> = 2.0V to 4.5V, I <sub>O</sub> = 50μA	Full		0.005	0.1	V
			V <sub>CC</sub> = 3.0V, I <sub>O</sub> = 4.0mA	Full		0.2	0.55	
			V <sub>CC</sub> = 4.5V, I <sub>O</sub> = 8.0mA	Full		0.3	0.55	
Input Leakage Current	I <sub>I</sub>	V <sub>CC</sub> = 0V to 5.5V, V <sub>I</sub> = 5.5V or GND		+25°C		±0.1	±1	μA
				Full			±2	
Off-State Output Current	I <sub>OZ</sub>	V <sub>I</sub> = V <sub>IH</sub> or V <sub>IL</sub> , V <sub>O</sub> = V <sub>CC</sub> or GND, V <sub>CC</sub> = 5.5V		+25°C		±0.1	±1	μA
				Full			±10	
Supply Current	I <sub>CC</sub>	V <sub>CC</sub> = 5.5V, V <sub>I</sub> = V <sub>CC</sub> or GND, I <sub>O</sub> = 0A		+25°C		0.1	2	μA
				Full			20	
Input Capacitance	C <sub>I</sub>			+25°C		6		pF

## DYNAMIC CHARACTERISTICS

(For test circuit, see Figure 2. Full = -40°C to +125°C, all typical values are measured at T<sub>A</sub> = +25°C, V<sub>CC</sub> = 3.3V and V<sub>CC</sub> = 5.0V respectively, unless otherwise noted.)

PARAMETER	SYMBOL	CONDITIONS			TEMP	MIN <sup>(1)</sup>	TYP	MAX <sup>(1)</sup>	UNITS
Propagation Delay	t <sub>PD</sub>	SHCP to Q7S <sup>(2)</sup> , see Figure 3	V <sub>CC</sub> = 3.0V to 3.6V	C <sub>L</sub> = 15pF	Full	0.5	8	16.5	ns
				C <sub>L</sub> = 50pF	Full	0.5	10	20	
			V <sub>CC</sub> = 4.5V to 5.5V	C <sub>L</sub> = 15pF	Full	0.5	6	11.5	ns
				C <sub>L</sub> = 50pF	Full	0.5	8	13.5	
		STCP to Qn <sup>(2)</sup> , see Figure 4	V <sub>CC</sub> = 3.0V to 3.6V	C <sub>L</sub> = 15pF	Full	0.5	8	14.5	ns
				C <sub>L</sub> = 50pF	Full	0.5	10.5	19	
			V <sub>CC</sub> = 4.5V to 5.5V	C <sub>L</sub> = 15pF	Full	0.5	6	10.5	ns
				C <sub>L</sub> = 50pF	Full	0.5	8	12.5	
		MR to Q7S <sup>(3)</sup> , see Figure 6	V <sub>CC</sub> = 3.0V to 3.6V	C <sub>L</sub> = 15pF	Full	0.5	6.5	14	ns
				C <sub>L</sub> = 50pF	Full	0.5	8	17.5	
			V <sub>CC</sub> = 4.5V to 5.5V	C <sub>L</sub> = 15pF	Full	0.5	5	9.5	ns
				C <sub>L</sub> = 50pF	Full	0.5	6	11.5	

**DYNAMIC CHARACTERISTICS (continued)**

(For test circuit, see Figure 2. Full = -40°C to +125°C, all typical values are measured at T<sub>A</sub> = +25°C, V<sub>CC</sub> = 3.3V and V<sub>CC</sub> = 5.0V respectively, unless otherwise noted.)

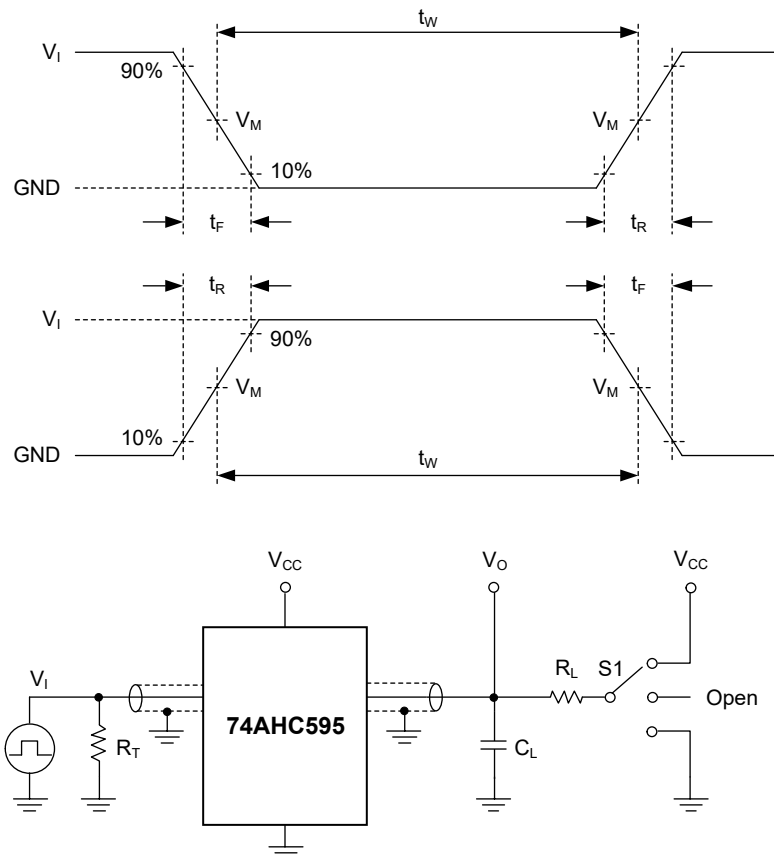
PARAMETER	SYMBOL	CONDITIONS			TEMP	MIN <sup>(1)</sup>	TYP	MAX <sup>(1)</sup>	UNITS
Enable Time <sup>(4)</sup>	t <sub>EN</sub>	OE̅ to Qn, see Figure 7	V <sub>CC</sub> = 3.0V to 3.6V	C <sub>L</sub> = 15pF	Full	0.5	7	14.5	ns
				C <sub>L</sub> = 50pF	Full	0.5	9	18	
			V <sub>CC</sub> = 4.5V to 5.5V	C <sub>L</sub> = 15pF	Full	0.5	5.5	11	ns
				C <sub>L</sub> = 50pF	Full	0.5	7	13	
Disable Time <sup>(5)</sup>	t <sub>DIS</sub>	OE̅ to Qn, see Figure 7	V <sub>CC</sub> = 3.0V to 3.6V	C <sub>L</sub> = 15pF	Full	0.5	7	14	ns
				C <sub>L</sub> = 50pF	Full	0.5	12	18.5	
			V <sub>CC</sub> = 4.5V to 5.5V	C <sub>L</sub> = 15pF	Full	0.5	7	12.5	ns
				C <sub>L</sub> = 50pF	Full	0.5	8	14	
Maximum Frequency	f <sub>MAX</sub>	SHCP or STCP, see Figure 3 and Figure 4	V <sub>CC</sub> = 3.0V to 3.6V		Full	80	165		MHz
			V <sub>CC</sub> = 4.5V to 5.5V		Full	110	165		
Pulse Width	t <sub>W</sub>	SHCP high or low, see Figure 3	V <sub>CC</sub> = 3.0V to 3.6V		Full	5			ns
			V <sub>CC</sub> = 4.5V to 5.5V		Full	5			
		STCP high or low, see Figure 4	V <sub>CC</sub> = 3.0V to 3.6V		Full	5			ns
			V <sub>CC</sub> = 4.5V to 5.5V		Full	5			
		MR̅ Low, see Figure 6	V <sub>CC</sub> = 3.0V to 3.6V		Full	5			ns
			V <sub>CC</sub> = 4.5V to 5.5V		Full	5			
Set-Up Time	t <sub>SU</sub>	DS to SHCP, see Figure 5	V <sub>CC</sub> = 3.0V to 3.6V		Full	3.5			ns
			V <sub>CC</sub> = 4.5V to 5.5V		Full	3			
		SHCP to STCP, see Figure 4	V <sub>CC</sub> = 3.0V to 3.6V		Full	8			ns
			V <sub>CC</sub> = 4.5V to 5.5V		Full	5			
Hold Time	t <sub>H</sub>	DS to SHCP, see Figure 5	V <sub>CC</sub> = 3.0V to 3.6V		Full	2.5			ns
			V <sub>CC</sub> = 4.5V to 5.5V		Full	2			
Recovery Time	t <sub>REC</sub>	MR̅ to SHCP, see Figure 6	V <sub>CC</sub> = 3.0V to 3.6V		Full	3			ns
			V <sub>CC</sub> = 4.5V to 5.5V		Full	2.5			
Power Dissipation Capacitance <sup>(6) (7)</sup>	C <sub>PD</sub>	f <sub>i</sub> = 1MHz, V <sub>I</sub> = GND to V <sub>CC</sub>			+25°C		180		pF

**NOTES:**

- Specified by design and characterization; not production tested.
- t<sub>PD</sub> is the same as t<sub>PHL</sub> and t<sub>PLH</sub>.
- t<sub>PD</sub> is the same as t<sub>PHL</sub> only.
- t<sub>EN</sub> is the same as t<sub>PZL</sub> and t<sub>PZH</sub>.
- t<sub>DIS</sub> is the same as t<sub>PLZ</sub> and t<sub>PHZ</sub>.
- C<sub>PD</sub> is used to determine the dynamic power dissipation (P<sub>D</sub> in μW).  

$$P_D = C_{PD} \times V_{CC}^2 \times f_i + \Sigma(C_L \times V_{CC}^2 \times f_o)$$
 where:  
 f<sub>i</sub> = Input frequency in MHz.  
 f<sub>o</sub> = Output frequency in MHz.  
 C<sub>L</sub> = Output load capacitance in pF.  
 V<sub>CC</sub> = Supply voltage in Volts.  
 $\Sigma(C_L \times V_{CC}^2 \times f_o)$  = Sum of outputs.
- All 9 outputs switching.

## TEST CIRCUIT



Test conditions are given in Table 1.

Definitions test circuit:

$R_L$ : Load resistance.

$C_L$ : Load capacitance (includes jig and probe).

$R_T$ : Termination resistance (equals to output impedance  $Z_O$  of the pulse generator).

S1: Test selection switch.

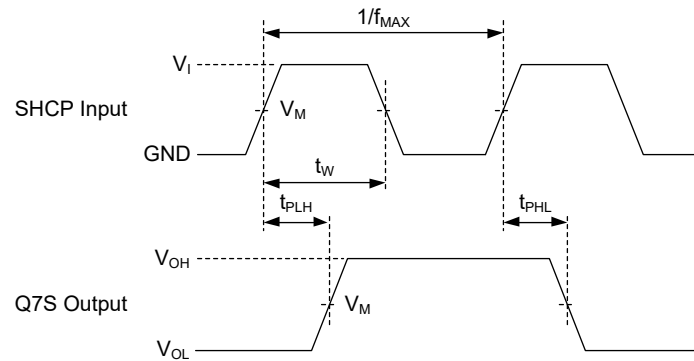
Figure 2. Test Circuit for Measuring Switching Times

Table 1. Test Conditions

SUPPLY VOLTAGE	INPUT		LOAD		S1 POSITION		
$V_{CC}$	$V_I$	$t_R, t_F$	$C_L$	$R_L$	$t_{PHL}, t_{PLH}$	$t_{PZH}, t_{PHZ}$	$t_{PZL}, t_{PLZ}$
2.0V to 5.5V	$V_{CC}$	$\leq 3.0\text{ns}$	15pF, 50pF	1k $\Omega$	Open	GND	$V_{CC}$



## WAVEFORMS

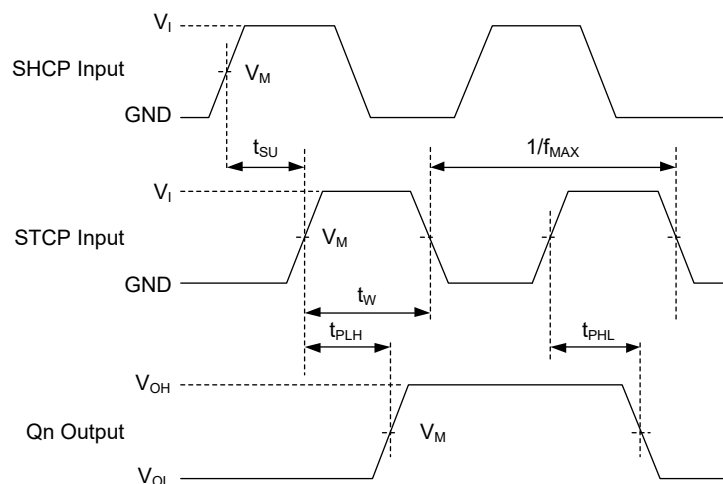


Test conditions are given in Table 1.

Measurement points are given in Table 2.

Logic levels:  $V_{OL}$  and  $V_{OH}$  are typical output voltage levels that occur with the output load.

**Figure 3. Shift Clock Pulse, Maximum Frequency and Input to Output Propagation Delays**



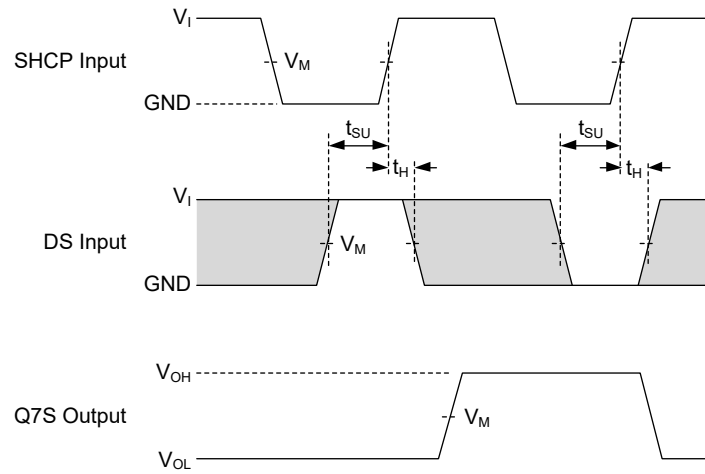
Test conditions are given in Table 1.

Measurement points are given in Table 2.

Logic levels:  $V_{OL}$  and  $V_{OH}$  are typical output voltage levels that occur with the output load.

**Figure 4. Storage Clock to Output Propagation Delays**

## WAVEFORMS (continued)

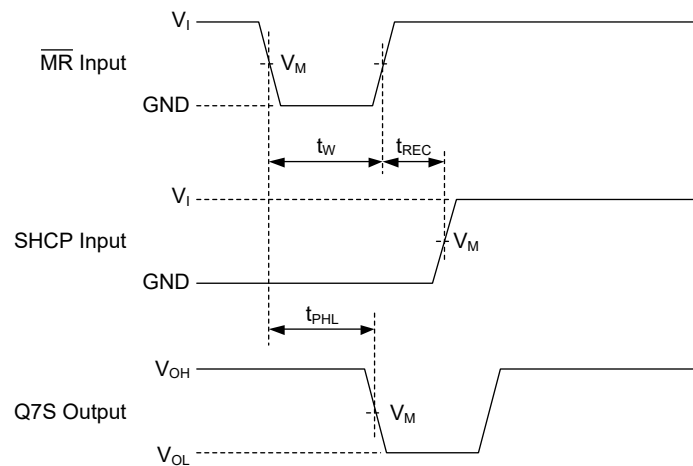


Test conditions are given in Table 1.

Measurement points are given in Table 2.

Logic levels:  $V_{OL}$  and  $V_{OH}$  are typical output voltage levels that occur with the output load.

**Figure 5. Data Set-Up and Hold Times**



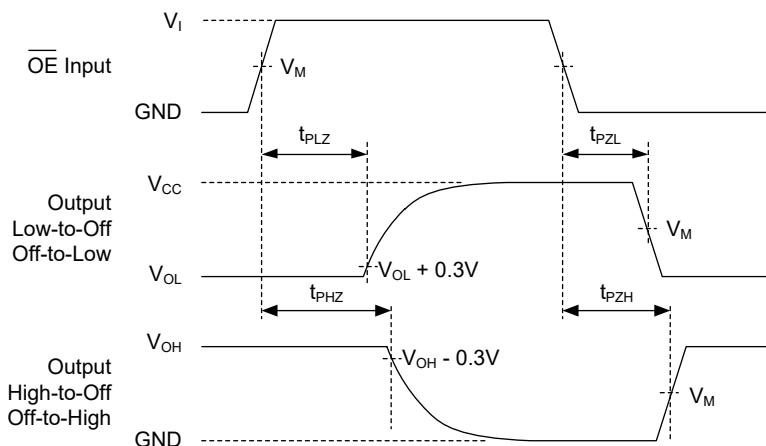
Test conditions are given in Table 1.

Measurement points are given in Table 2.

Logic levels:  $V_{OL}$  and  $V_{OH}$  are typical output voltage levels that occur with the output load.

**Figure 6. Master Reset to Output Propagation Delays**

## WAVEFORMS (continued)



Test conditions are given in Table 1.

Measurement points are given in Table 2.

Logic levels:  $V_{OL}$  and  $V_{OH}$  are typical output voltage levels that occur with the output load.

Figure 7. Enable and Disable Times

Table 2. Measurement Points

SUPPLY VOLTAGE	INPUT	OUTPUT
$V_{CC}$	$V_M^{(1)}$	$V_M$
2.0V to 5.5V	$0.5 \times V_{CC}$	$0.5 \times V_{CC}$

NOTE:

1. The measurement points should be  $V_{IH}$  or  $V_{IL}$  when the input rising or falling time exceeds 3.0ns.

## REVISION HISTORY

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

### SEPTEMBER 2022 – REV.A to REV.A.1

Page

Updated Electrical Characteristics section .....	6
Updated Dynamic Characteristics section.....	7
Added SOIC-16 package .....	All

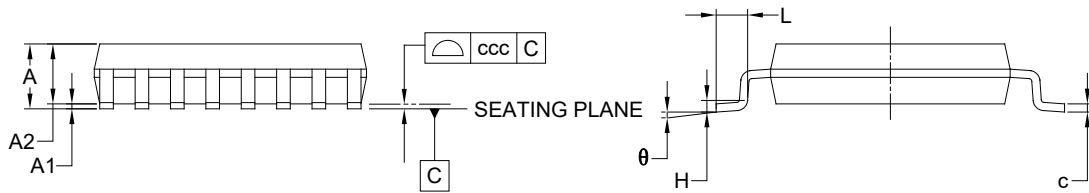
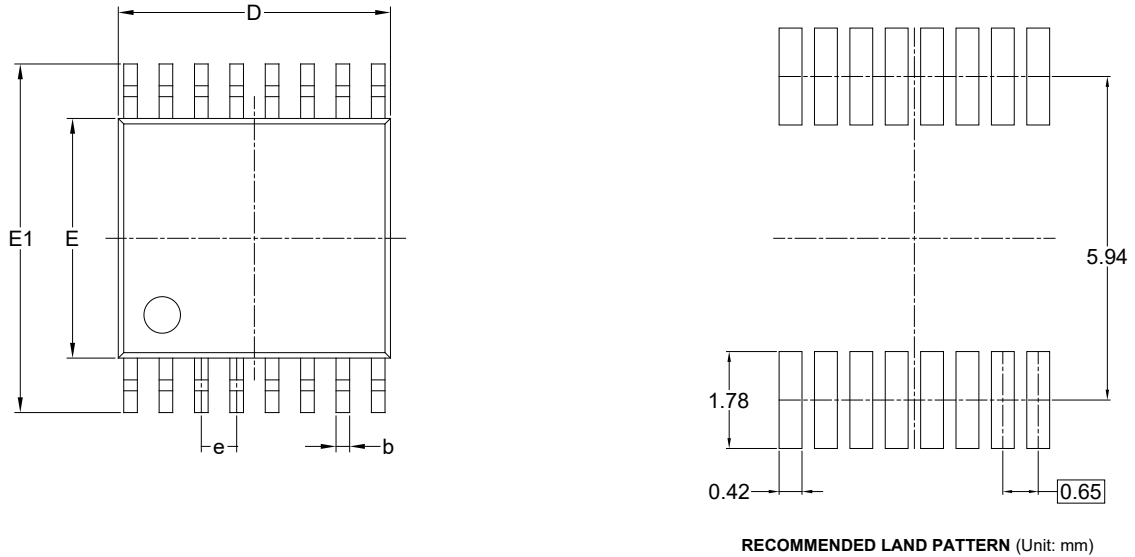
### Changes from Original (SEPTEMBER 2021) to REV.A

Page

Changed from product preview to production data.....	All
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## PACKAGE OUTLINE DIMENSIONS

### TSSOP-16



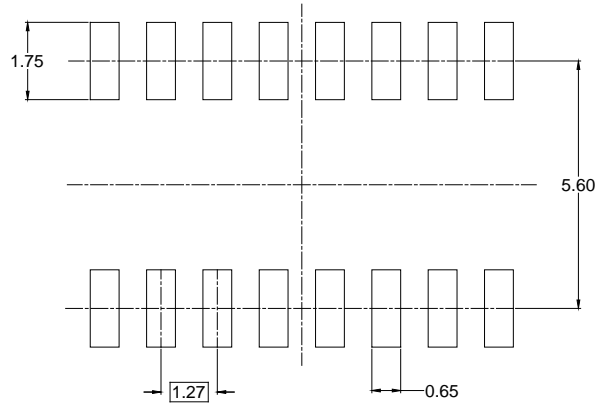
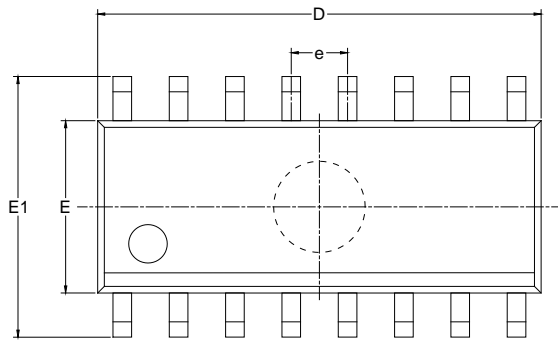
Symbol	Dimensions In Millimeters		
	MIN	MOD	MAX
A	-	-	1.200
A1	0.050	-	0.150
A2	0.800	-	1.050
b	0.190	-	0.300
c	0.090	-	0.200
D	4.860	-	5.100
E	4.300	-	4.500
E1	6.200	-	6.600
e	0.650 BSC		
L	0.450	-	0.750
H	0.250 TYP		
$\theta$	0°	-	8°
ccc	0.100		

#### NOTES:

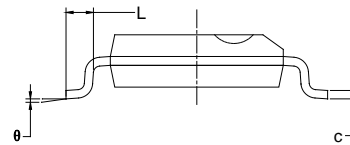
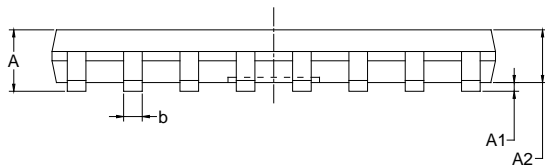
1. This drawing is subject to change without notice.
2. The dimensions do not include mold flashes, protrusions or gate burrs.
3. Reference JEDEC MO-153.

## PACKAGE OUTLINE DIMENSIONS

### SOIC-16



RECOMMENDED LAND PATTERN (Unit: mm)



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	MIN	MAX	MIN	MAX
A	1.350	1.750	0.053	0.069
A1	0.100	0.250	0.004	0.010
A2	1.350	1.550	0.053	0.061
b	0.330	0.510	0.013	0.020
c	0.170	0.250	0.006	0.010
D	9.800	10.200	0.386	0.402
E	3.800	4.000	0.150	0.157
E1	5.800	6.200	0.228	0.244
e	1.27 BSC		0.050 BSC	
L	0.400	1.270	0.016	0.050
θ	0°	8°	0°	8°

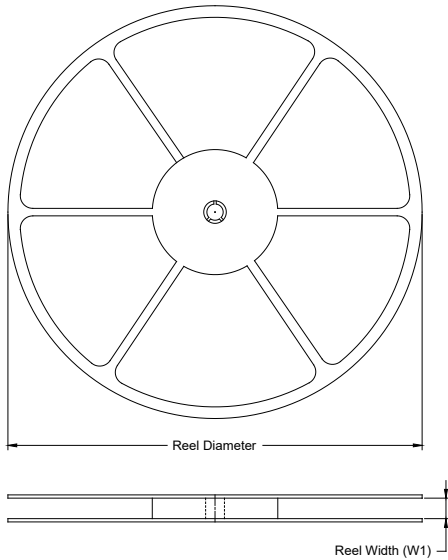
NOTES:

1. Body dimensions do not include mode flash or protrusion.
2. This drawing is subject to change without notice.

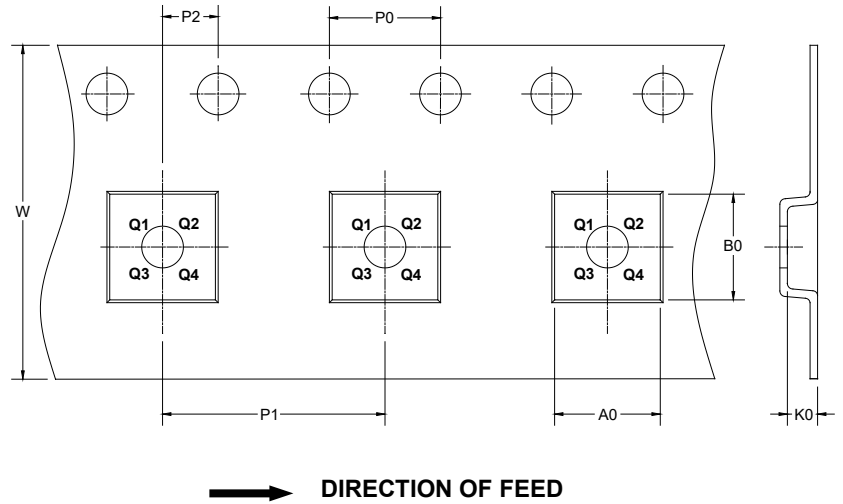
# PACKAGE INFORMATION

## TAPE AND REEL INFORMATION

### REEL DIMENSIONS



### TAPE DIMENSIONS



NOTE: The picture is only for reference. Please make the object as the standard.

### KEY PARAMETER LIST OF TAPE AND REEL

Package Type	Reel Diameter	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P0 (mm)	P1 (mm)	P2 (mm)	W (mm)	Pin1 Quadrant
TSSOP-16	13"	12.4	6.90	5.60	1.50	4.0	8.0	2.0	12.0	Q1
SOIC-16	13"	16.4	6.50	10.30	2.10	4.0	8.0	2.0	16.0	Q1

DD0001

## PACKAGE INFORMATION

### CARTON BOX DIMENSIONS



NOTE: The picture is only for reference. Please make the object as the standard.

### KEY PARAMETER LIST OF CARTON BOX

Reel Type	Length (mm)	Width (mm)	Height (mm)	Pizza/Carton
13"	386	280	370	5

DD0002